

Semi-linear response and RMT for the heating rate of cold atoms in vibrating traps

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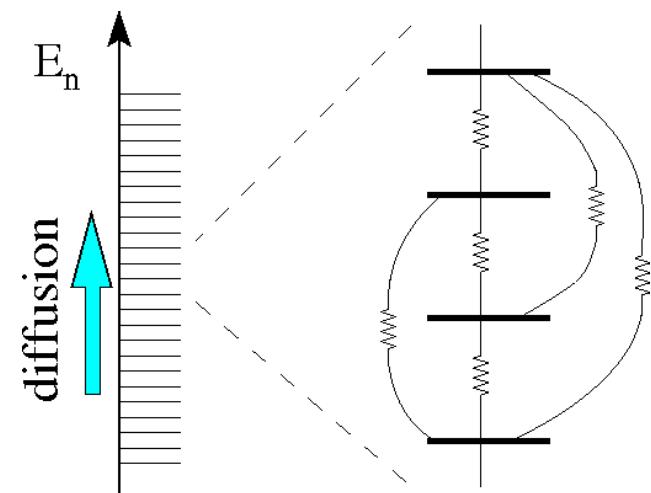
References:

A. Stotland, R. Budoyo, T. Peer, T. Kottos and D. Cohen, JPA (FTC) (2008)

A. Stotland, D. Cohen and N. Davidson, EPL (2009)

A. Stotland, T. Kottos, and D. Cohen, ArXiv (2009)

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\$DIP

\$BSF

\$FOR760

Diffusion and Energy absorption

Driven chaotic system with Hamiltonian $\mathcal{H}(R(t))$

R = some control parameter

\dot{R} = rate of the (noisy) driving

~ diffusion in energy space:

$D = G_{\text{diffusion}} \overline{\dot{R}^2}$

There is a dissipation-diffusion relation.
In the canonical case $\dot{E} = D/T$.

~ energy absorption:

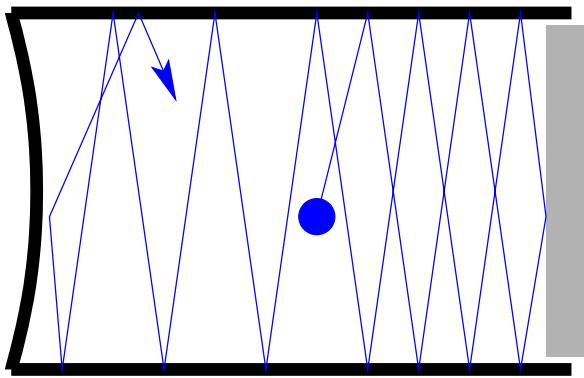
$\dot{E} = G_{\text{absorption}} \overline{\dot{R}^2}$

Below we use for G scaled units.

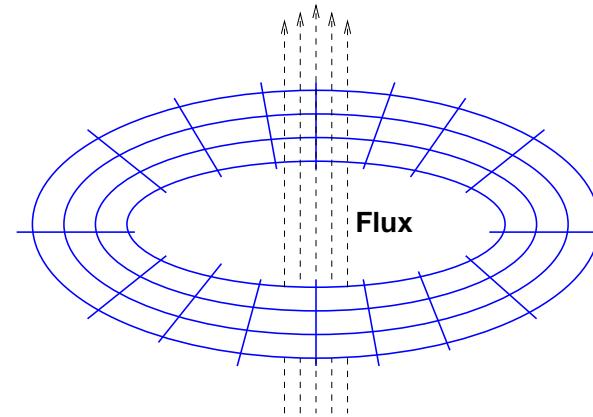
[Ott, Brown, Grebogi, Wilkinson, Jarzynski, Cohen]

Models

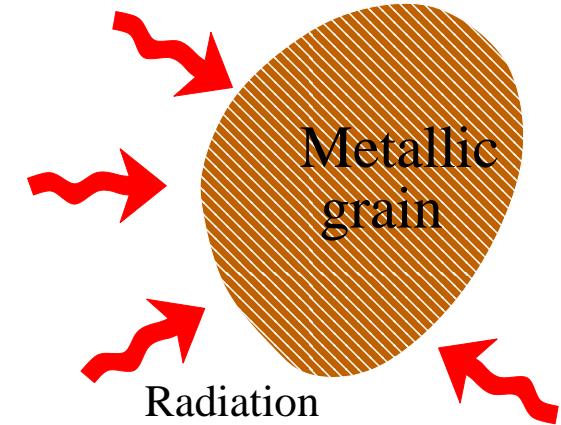
$$\mathcal{H} = \{E_n\} - R(t)\{V_{nm}\}$$



2-D box with a vibrating wall.



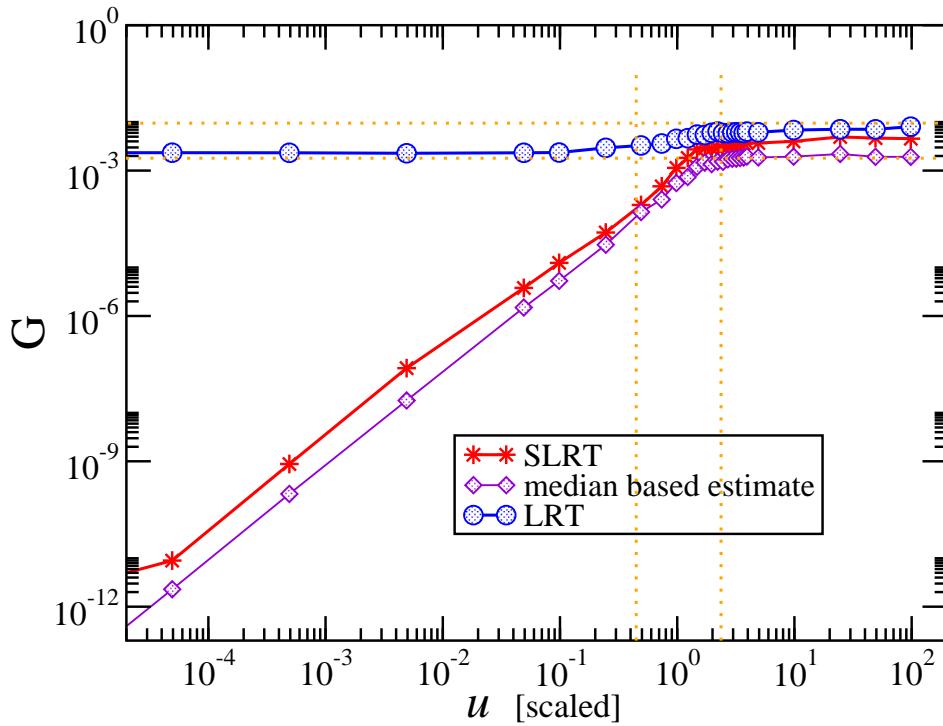
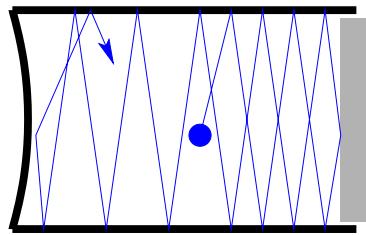
Disordered ring driven by EMF.



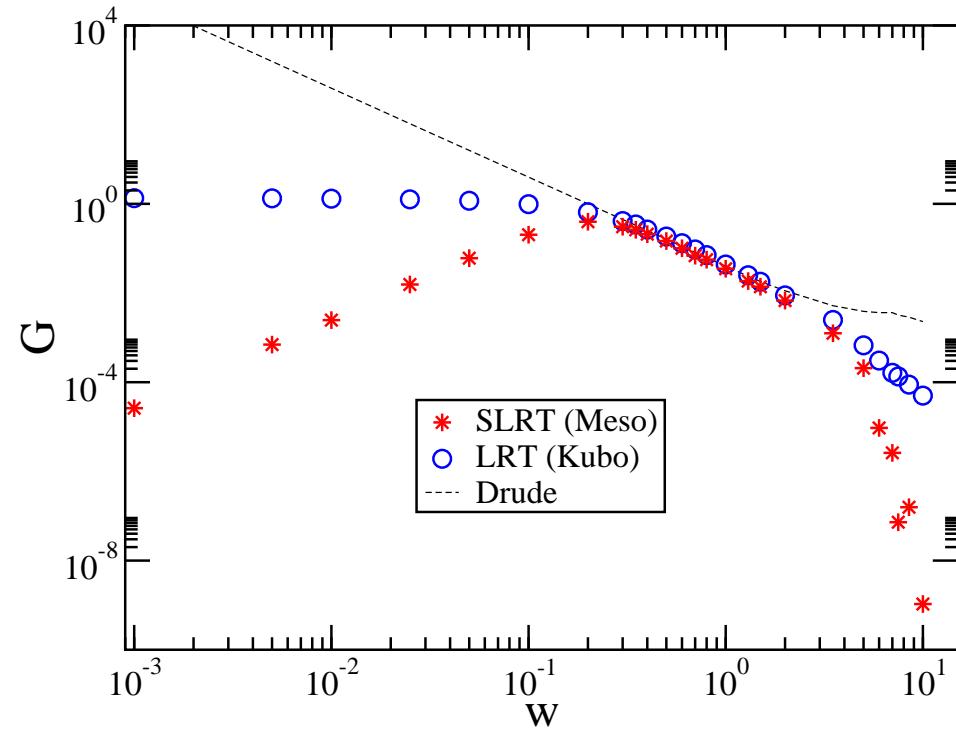
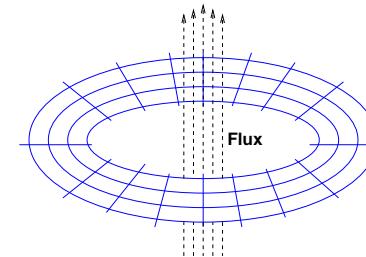
Radiation absorbtion by metallic grains.

- [1] D. Cohen, T. Kottos and H. Schanz, JPA (2006)
- [2] S. Bandopadhyay, Y. Etzioni and D. Cohen, EPL (2006)
- [3] M. Wilkinson, B. Mehlig and D. Cohen, EPL (2006)
- [4] D. Cohen, PRB (2007)
- [5] A. Stotland, R. Budoyo, T. Peer, T. Kottos and D. Cohen, JPA(FTC) (2008)
- [6] A. Stotland, D. Cohen and N. Davidson, EPL (2009)
- [7] A. Stotland, T. Kottos and D. Cohen, ArXiv (2009)

Some results



u - strength of the deformation



W - strength of the disorder

The resistor network calculation

$$\mathcal{H} = \{E_n\} + f(t)\{V_{nm}\}$$

$$G = \pi \varrho_E \langle\langle |V_{mn}|^2 \rangle\rangle_{\text{SLRT}}$$

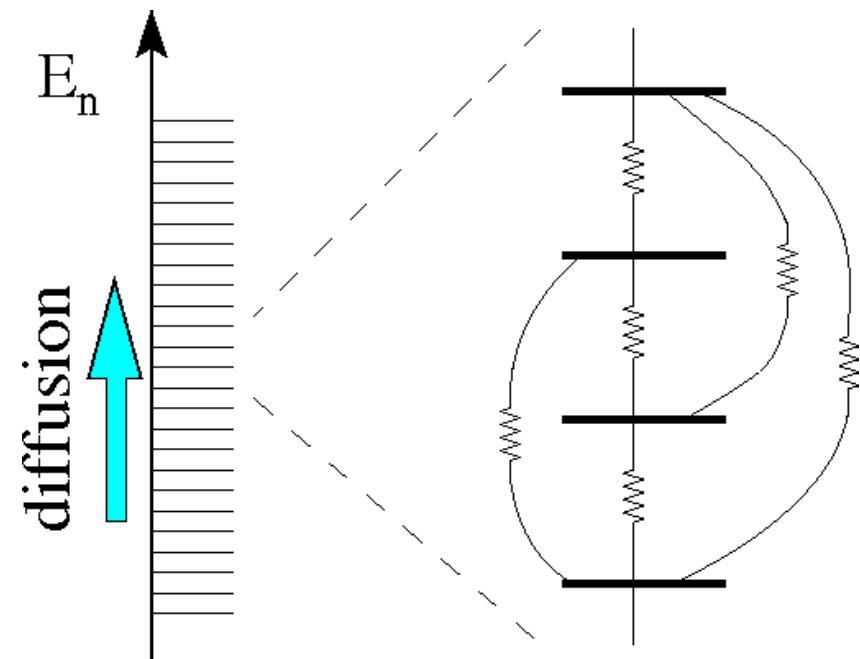
$$\tilde{S}(\omega) = \text{FT } \langle \dot{f}(t) \dot{f}(0) \rangle$$

$$g_{nm} = 2\varrho_F^{-3} \frac{|V_{nm}|^2}{(E_n - E_m)^2} \tilde{S}(E_n - E_m)$$

$\langle\langle |V_{mn}|^2 \rangle\rangle_{\text{SLRT}} \equiv$ inverse resistivity

$$\langle\langle |V_{mn}|^2 \rangle\rangle_{\text{harmonic}} \ll \langle\langle |V_{mn}|^2 \rangle\rangle_{\text{SLRT}} \ll \langle\langle |V_{mn}|^2 \rangle\rangle_{\text{algebraic}}$$

$$g_{\text{SLRT}} \equiv \frac{\langle\langle |V_{mn}|^2 \rangle\rangle_{\text{SLRT}}}{\langle\langle |V_{mn}|^2 \rangle\rangle_{\text{algebraic}}}$$



SLRT vs. LRT

$$\mathcal{H}(R(t)) \approx \mathcal{H}_0 + f(t)V$$

$$\mathcal{H}_0 = \mathcal{H}(R_0)$$

$$f(t) = R(t) - R_0$$

$$V = \frac{\partial \mathcal{H}}{\partial R}$$

$$\tilde{C}(\omega) = \text{FT } \langle V(t)V(0) \rangle$$

$$\tilde{S}(\omega) = \text{FT } \langle \dot{f}(t)\dot{f}(0) \rangle$$

Linear response implies

$$\tilde{S}(\omega) \mapsto \lambda \tilde{S}(\omega) \implies D \mapsto \lambda D$$

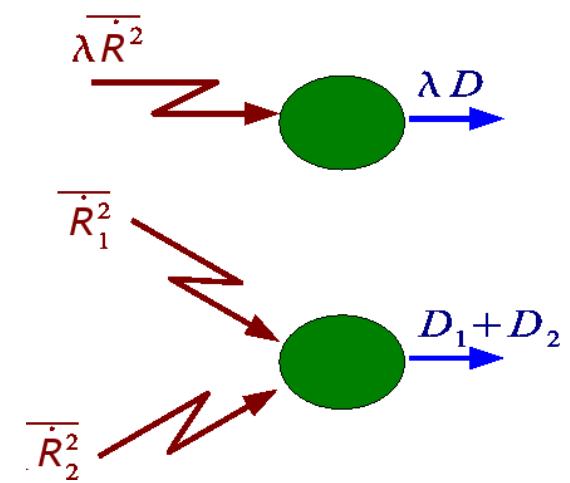
$$\tilde{S}(\omega) \mapsto \sum_i \tilde{S}_i(\omega) \implies D \mapsto \sum_i D_i$$

Kubo formula:

$$D = \int \tilde{C}(\omega) \tilde{S}(\omega) d\omega$$

SLRT example:

$$D = \left[\int \mu(\omega) [\tilde{S}(\omega)]^{-1} d\omega \right]^{-1}$$

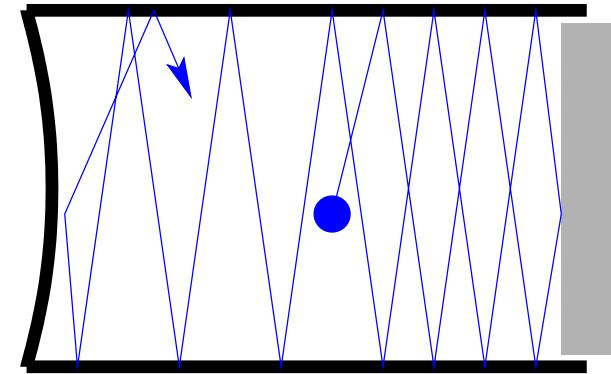


The model

A particle in a 2-D box with a vibrating wall.

Deforming potential:

deformed wall / smooth Gaussian / s-scatterer



The Hamiltonian in the $\mathbf{n} = (n_x, n_y)$ basis:

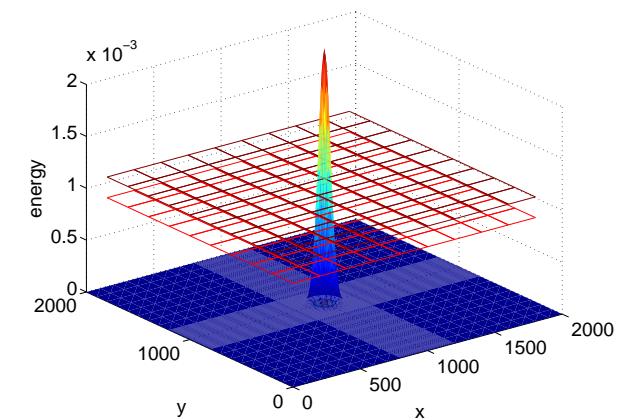
$$\mathcal{H} = \text{diag}\{E_{\mathbf{n}}\} + \textcolor{blue}{u}\{U_{\mathbf{nm}}\} + f(t)\{\textcolor{red}{V}_{\mathbf{nm}}\}$$

The matrix elements for the wall displacement:

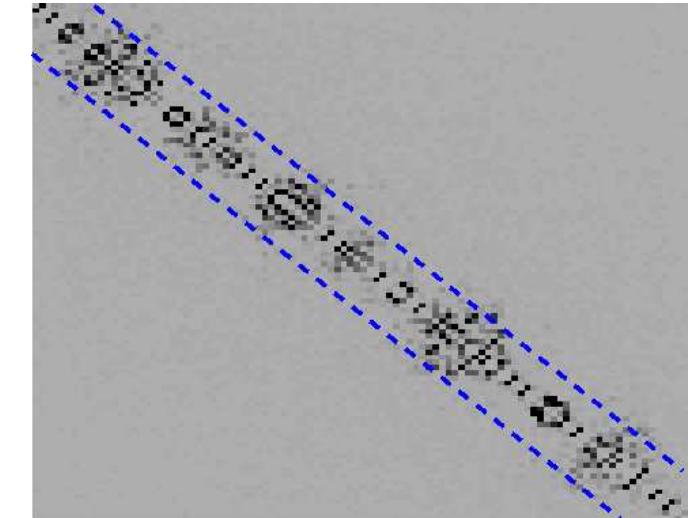
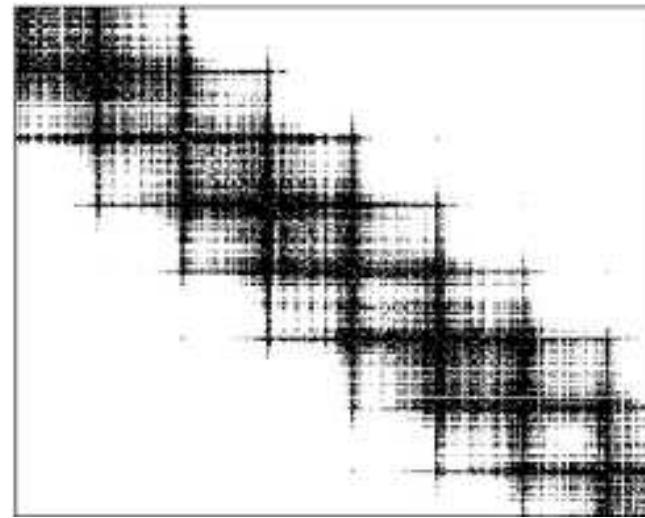
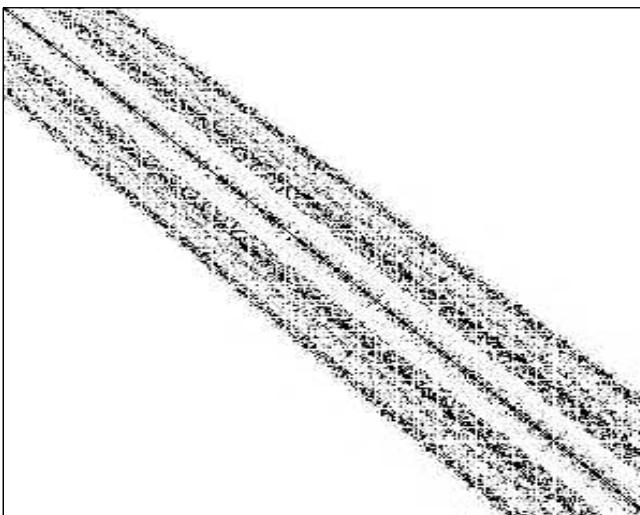
$$V_{\mathbf{nm}} = -\delta_{n_y, m_y} \times \frac{\pi^2}{\mathbf{M} L_x^3} n_x m_x \quad [\text{sparse}]$$

The Hamiltonian in the E_n basis:

$$\mathcal{H} = \text{diag}\{E_n\} + f(t)\{\textcolor{red}{V}_{\mathbf{nm}}\}$$



Matrices - Gallery

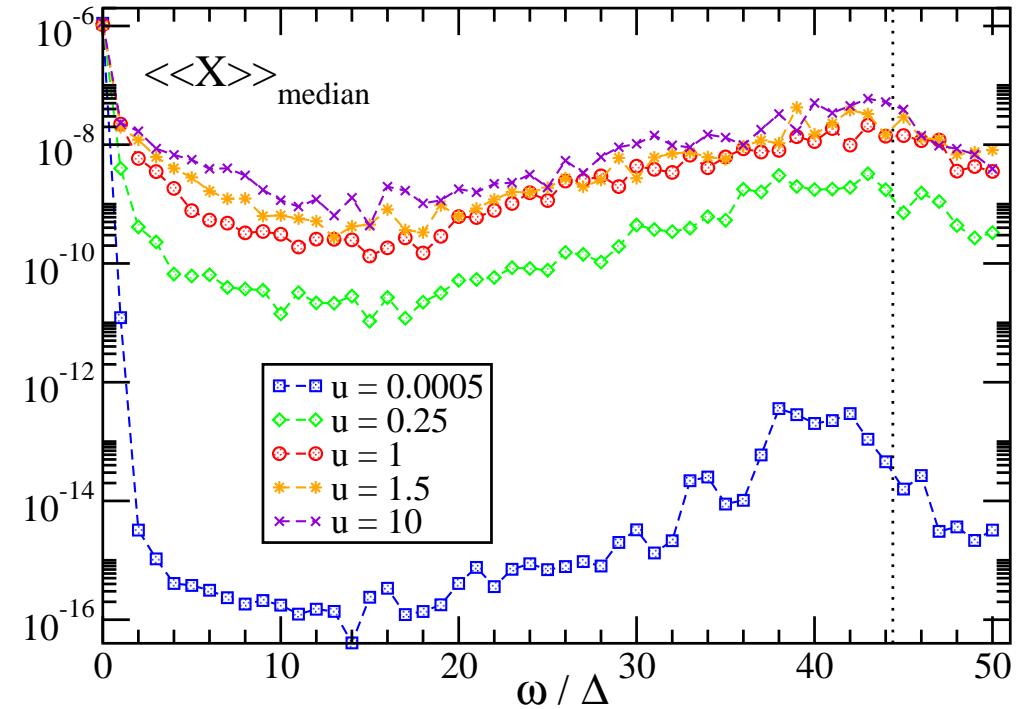
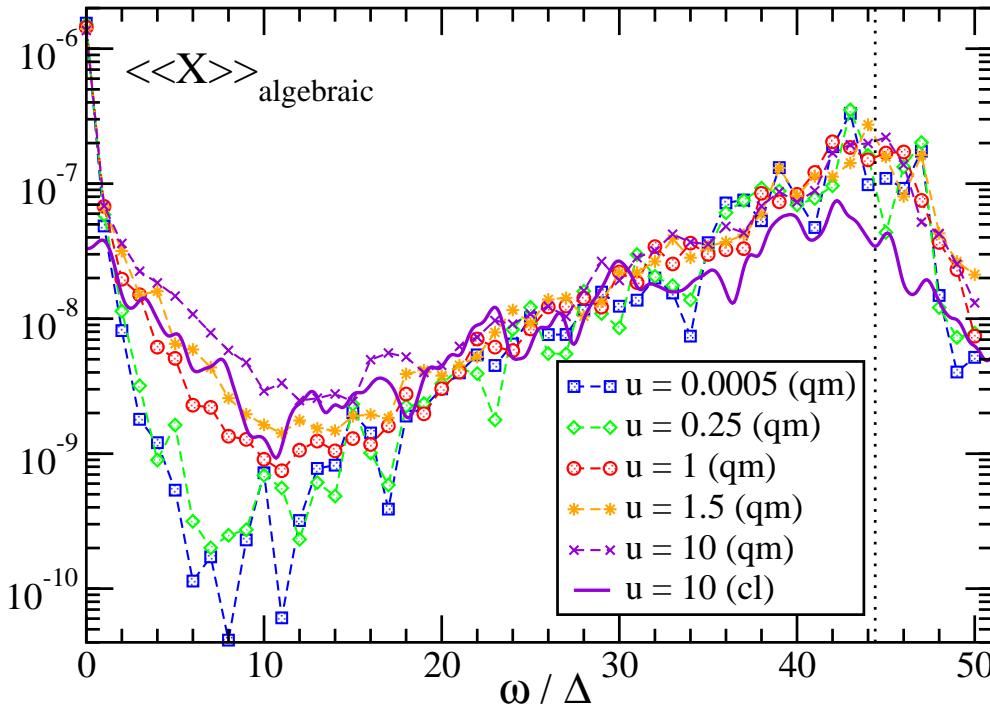


$$\tilde{C}(\omega) \equiv \langle\langle |V_{nm}|^2 \rangle\rangle_{\text{algebraic}} = \left\langle \sum_n |V_{nn_0}|^2 \delta(\omega - (E_n - E_{n_0})) \right\rangle_{\text{algebraic}}$$

Sparsity and texture are not reflected by $\tilde{C}(\omega)$!

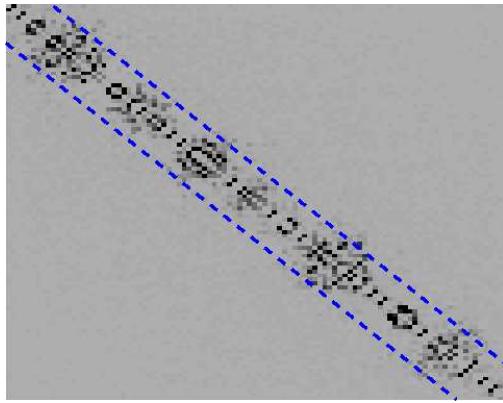
$$G = \pi \varrho_E \langle\langle |V_{mn}|^2 \rangle\rangle$$

Spectral functions



$$\langle\langle |V_{nm}|^2 \rangle\rangle_{\text{algebraic/median}} = \left\langle \sum_n |V_{nn_0}|^2 \delta(\omega - (E_n - E_{n_0})) \right\rangle_{\text{algebraic/median}}$$

$\{|V_{nm}|^2\}$ as a random matrix $\{X\}$

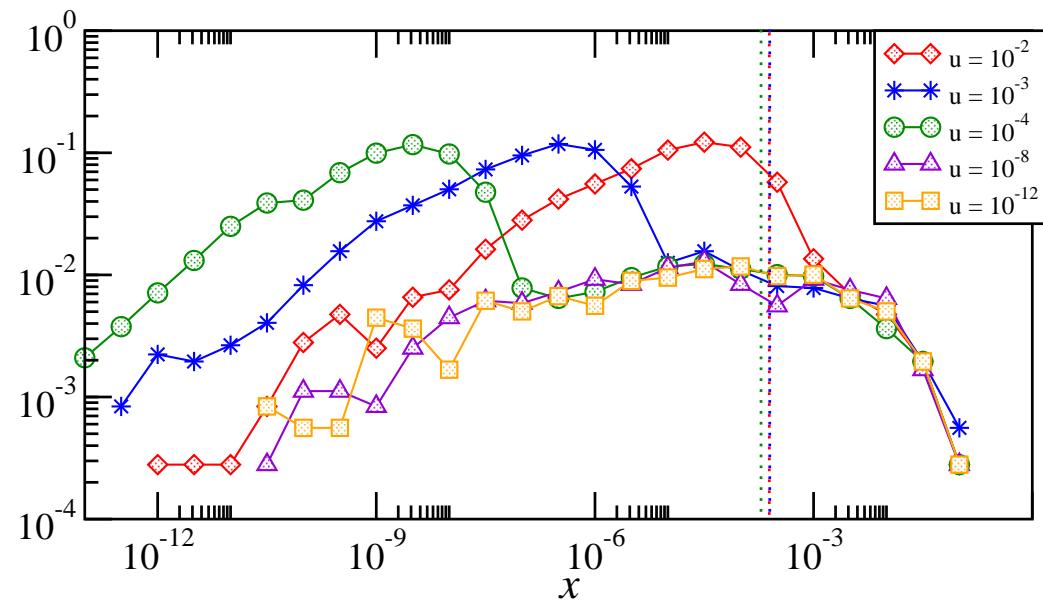


- bandwidth
- texture
- sparsity

$$q \equiv \frac{\langle\langle x \rangle\rangle_g}{\langle\langle x \rangle\rangle_a}$$

$$p \equiv \text{Prob} (X > \langle X \rangle)$$

Histogram of X :



$X \sim \text{LogNormal}$

Averages:

Algebraic: $\langle\langle x \rangle\rangle_a = \langle x \rangle$

Harmonic: $\langle\langle x \rangle\rangle_h = [\langle 1/x \rangle]^{-1}$

Geometric: $\langle\langle x \rangle\rangle_g = \exp[\langle \log x \rangle]$

For “log - wide” distributions:

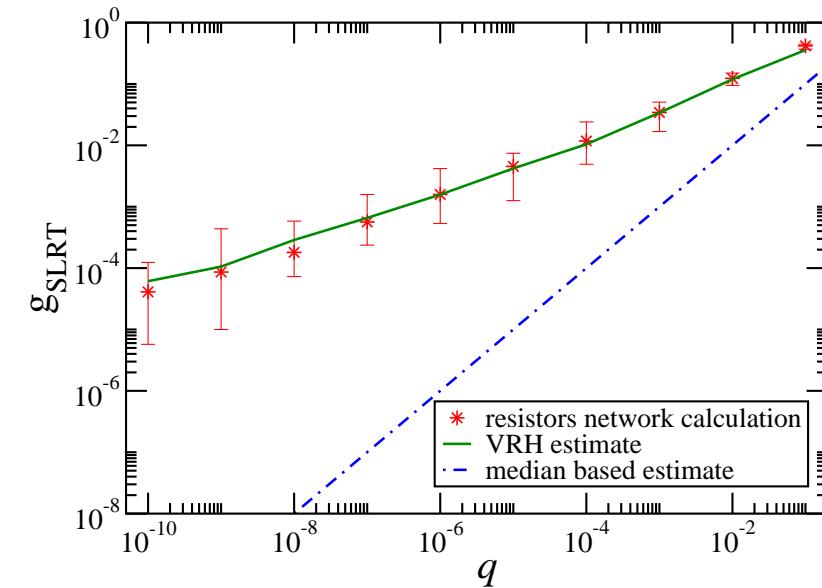
$\langle\langle x \rangle\rangle_h \ll \langle\langle x \rangle\rangle_g \ll \langle\langle x \rangle\rangle_a$

The RMT modeling - Results

- Log-normal RMT modeling

For the rectangular $\tilde{S}(\omega)$ of width ω_c

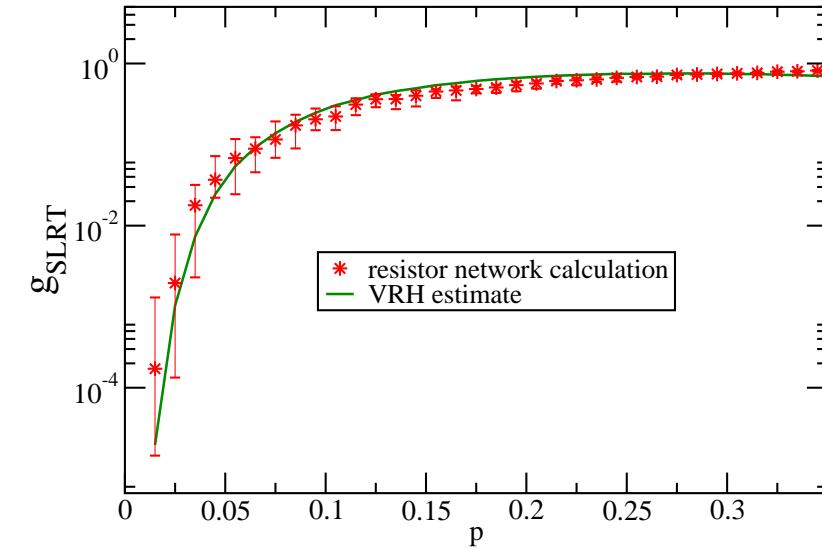
$$g_{\text{SLRT}} \approx q \exp \left[2 \sqrt{-\ln q \ln(\omega_c/\Delta)} \right]$$



- Log-box RMT modeling

For the exponential $\tilde{S}(\omega)$ of width ω_c

$$g_{\text{SLRT}} \approx \frac{1}{p} \exp \left[-2 \sqrt{\frac{\Delta}{p \omega_c}} \right]$$



Conclusions

(*) Wigner (~ 1955):

The perturbation is represented by a random matrix whose elements are taken from a **Gaussian** distribution.

Not always...

1. No “strong quantum chaos” \Rightarrow log-normal distribution.
2. The heating process \sim a percolation problem.
3. Resistors network calculation to get G_{SLRT} .
4. Generalization of the VRH estimate
5. SLRT is essential whenever the distribution of matrix elements is wide (“sparsity”) or if the matrix has “texture”.

Appendix: Generalized VRH

A typical matrix element for connected transitions:

$$\left(\frac{\omega}{\Delta}\right) \text{Prob}\left(x > x_\omega\right) \sim 1$$

Generalized VRH estimate:

$$G_{\text{SLRT}} = \int x_\omega \tilde{S}(\omega) d\omega$$

In the standard case (strong disorder):

$$\begin{aligned} \text{Prob}(x) &= \text{log-box} & \tilde{S}(\omega) &\propto \exp\left(-\frac{|\omega|}{T}\right) \\ x_\omega &\approx v_F^2 \exp\left(\frac{\Delta_l}{|\omega|}\right) & G_{\text{SLRT}} &\propto \int \exp\left(-\frac{|\omega|}{T}\right) \exp\left(\frac{\Delta_l}{|\omega|}\right) d\omega \end{aligned}$$